

Notice of References Cited	Application/Control No. 10/606,834	Applicant(s)/Patent Under Reexamination NAKAHARA ET AL.	
	Examiner Thomas L Dickey	Art Unit 2826	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,811,353	03-1989	Noda et al.	372/45
*	C	US-2002/0131466	09-2002	Salvatore et al.	372/50
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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*	U	Itaya et al., "New 1.5 micron Wavelength GaInAsP/InP Distributed Feedback Laser", Electronics Letters, vol. 18, No. 23, Nov. 1982, pp. 1006-1008.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.